

32Mbit Quad-SPI Pseudo-SRAM Data Sheet

CSS3204S

Version: 1



Cascadeteq Inc

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CSS3204S 32Mb Quad-SPI Pseudo-SRAM

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The CSS3204S is general part number of 32Mb 1.8V Quad-SPI Pseudo-SRAM product family. The package type and detailed part number refers to 3. Package Information, 4 Ordering Information and 4.1 Part Number.

1. Feature and Specification

Interface:

SPI/QPI with SDR mode

Single Supply Voltage:

VDD=1.62 to 1.98V

Performance:

Clock rate up to 84MHz

Organization:

32Mb, 4M x 8bits

Addressable Bit Range:

A[21:0]

Page Size:

1024 bytes

Refresh:

Self-managed

Operating Temperature Range (refer to 4.1 Part Number)

 $Tc = -40^{\circ}C$ to $+85^{\circ}C$ (standard)

Tc = -40°C to +105°C (extended)

Maximum Standby Current

300μA @ 105°C

200μA @ 85°C

Typical Halfsleep[™] Mode with data retained

20μA @ 25°C

 50Ω Output Drive Strength LVCMOS.

Linear Burst:

Supported up to 84MHz and can cross page boundary as long as tCEM is met.

Software Reset

Ultra Low Power Halfsleep[™] Mode with data retention.

2. Description

The feature of the CSS3204S is a high speed, low pin count interface. It has 4 SDR I/O pins and operates in SPI(serial peripheral interface) or QPI (quad peripheral interface) mode with frequencies up to 84 MHz. The data input (A/DQ) to the memory relies on clock (CLK) to latch all instructions, addresses and data. It is most suitable for low-power

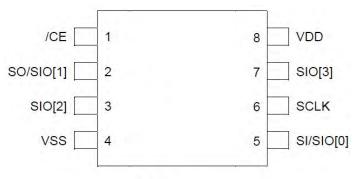


and low cost applications like wearable or IoT devices. It incorporates a seamless self-managed refresh mechanism. Hence it does not require the support of DRAM refresh from system host. The self-refresh feature is a special design to maximize performance of memory read operation.

3. Package Information

The CSS3204SS is available in standard package including 8-lead SOP-8L(150) The CSS3204SU is available in advanced package including 8-lead USON-8L(3x2mm)

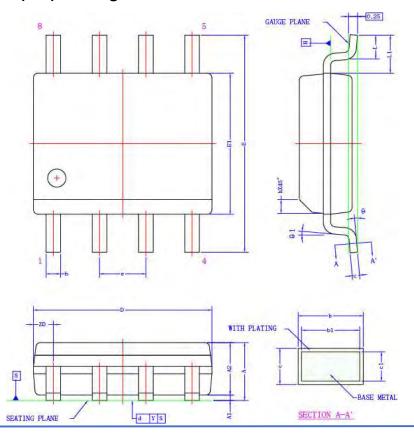
Package Type: SOP/USON



Top View

3.1 Package Outline Drawing

3.1.1 SOP-8L (150) Drawing



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SYMBOL	1 7 3	DIMENSION (MM)		16	DIMENSION (MIL)			
	MIN.	-	MAX.	MIN.	NOM.	MAX.		
A	1,35	1.60	1.75	53	63	69		
A1	0.10	0,15	0.25	4	6	10		
A2	1,35	1.45	1,55	53	57	61		
ь	0,31	-	0.51	12		20		
ь1	0.28	0.40	0.48	11	16	19		
c	0.17	1-	0.25	7	-	10		
c1	0.17	0,20	0,23	7	8	9		
D	4,80	4.90	5,00	189	193	197	NOTE :	
E		6,00 BSC			236 BSC			
E1	3,80	3,90	4,00	150	154	157	2, DIMENS	
В		1,27 BSC			50 BSC		BURRS,	
L	0.40	0.66	1,27	16	26	50	0.15mm DIMENS	
L1		1.05 REF		_	41 REF			
ZD	1000	0.55 REF			22 REF		PER SI	
h	0.25	0,38	0.50	10	15	20	'D' AN	
Y	1,4	-	0.10	-	-	4	3, DIMENS	
0	0°	-	8°	0°	-	8"	.P. DII	
01	0"			.0°	-	(14 ,	THE DA	

1, REPER TO JEDEC STD: NS-012 AA,

, DIMENSION "D" DOES NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURRS, MOLD FLASH, PROTRUSION AND GATE BURRS SHALL NOT EXCEED 0.15mm PER SIDE.

DIMENSION "E1" DOES NOT INCLUDE INTERLEAD MOLD FLASH OR PROTRUSION, INTERLEAD MOLD FLASH OR PROTRUSION SHALL NOT EXCEED 0,25mm PER SIDE.

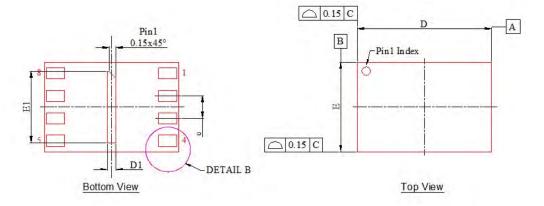
'D' AND 'E1' DIMENSIONS ARE DETERMIND AT DATUM H ,

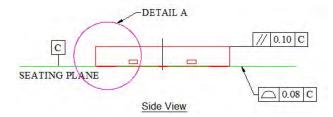
DIMENSION "6" DOES NOT INCLUDE DAMBAR PROTRUSION,

ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.10 $_{mm}$ TOTAL IN EXCESS OF THE $^{\circ}$ b' DIMENSION AT MAXIMUM MATERIAL CONDITION,

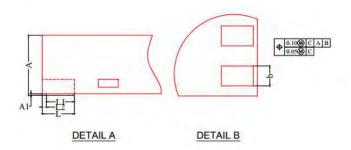
THE DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OF THE POOT,

3.1.2 USON-8L (3x2mm) Drawing









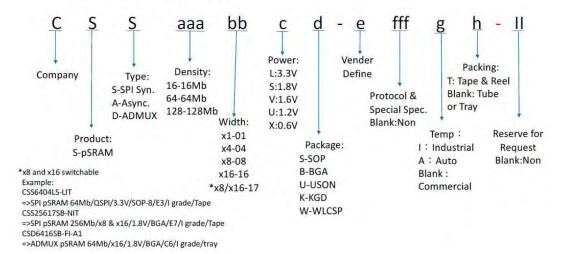
Comb.1	MILLIMETERS					
A A1 D D1	MIN.	NOM.	MAX			
A	0.40	0.45	0.50			
A1	0.00		0.05			
D	2.90	3.00	3.10			
D1	0.10	0.20	0.30			
E	1.90	2.00	2.10			
E1	1.50	1.60	1.70			
L	0.40	0.45	0.50			
L1	0.30					
L2			0.15			
b	0.20	0.25	0.30			
e	0.50 BSC					

NOTE:

- 1. Scale 1:4
- 2. ALL DIMENSIONS AND TOLERANCES TAKE REFERANCE TO JEDEC MO-229
- 3. DIMENSION "b" APPLIES TO METALLIZED TERMINAL AND IS MEASURED BETWEEN 0.15MM AND 0.30MM FROM THE TERMINAL TIP. IF THE TERMINAL HAS OPTIONAL RADIUS ON THE OTHER END OF THE TERMINAL, THE DIMENSION B SHOULD NOT BE MEASURED IN THAT RADIUS AREA.

4. Ordering Information

Product Naming Rule:



4.1 Part Number:

Part Number	Density	Temperature	Note
CSS3204SU-L-A2	32Mb	0-70C	USON
CSS3204SU-LI-A2	32Mb	-40~85C	USON
CSS3204SS-L-A2	32Mb	0-70C	SOP8
CSS3204SS-LI-A2	32Mb	-40~85C	SOP8
CSS3204SS-LJ-A2	32Mb	-40~105C	SOP8

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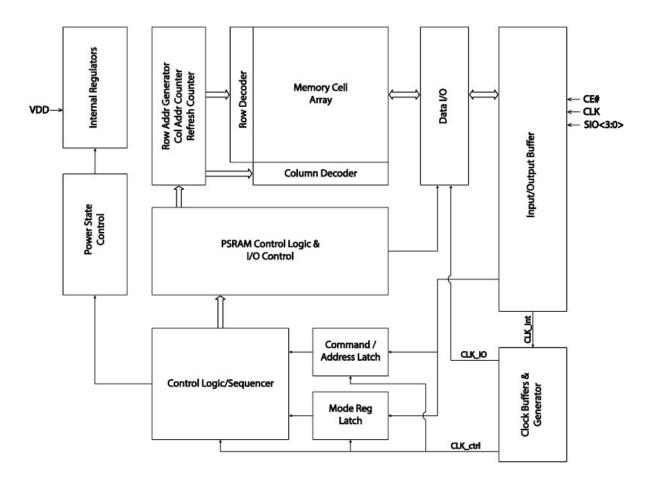
5. Package Ball Signal Table

Table 1 Signals Table

Symbol	Туре	SPI Mode	Comments						
VDD	Power		Core suppl	y 1.8V					
VSS	Ground		Core supply ground						
CE#	Input	Chip select, ac	Chip select, active low. When CE#=1, chip is in standby						
CLK	Input		Clock Signal						
SI/SIO[0]	Ю	Serial Input	IO[0]*	IO[0]					
SO/SIO[1]	Ю	Serial	IO[1] *	IO[1]					
SIO[2]	10	IO[2]* IO[2]							
SIO[3]	10		IO[3] *	IO[3]					

Note: * Quad SPI mode

6. Function Diagram

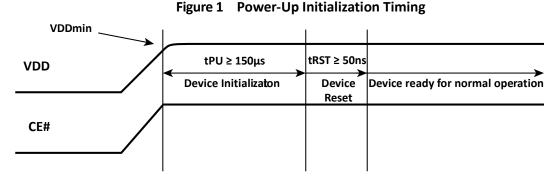




7. Powerup Initialization

This SPI/QPI product includes an on-chip voltage sensor used to start the self-initialization process. When VDD reaches a stable level at or above minimum VDD, the device will require 150µs and user-issued RESET Operation to complete its self-initialization process. From the beginning of power ramp to the end of the 150µs period, CLK should remain LOW, CE# should remain HIGH (track VDD within 200mV) and SI/SO/SIO[3:0] should remain LOW.

After the Device Reset tRST \ge 50ns period the device is ready for normal operation.



8. Interface Description

8.1 Address Space

SPI/QPI PSRAM device is byte-addressable. 32M device is addressed with A[21:0].

8.2 Page Size

Page size is 1K (CA[9:0]). The device operates in a linear bursting address sequence that crosses page boundary in a continuous manner. Note however that burst operations which cross page boundary have a lower max input clock frequency limit of 84MHz, and it can cross page boundary one time only in a burst.

8.3 Drive Strength

The device powers up in 50Ω .

8.4 Power-On Status

The device powers up in SPI Mode. It is required to have CE# high before beginning any operations.



8.5 Command/Address Latching Truth Table

The device recognizes the following commands specified by the various input methods

Table 2 True Table

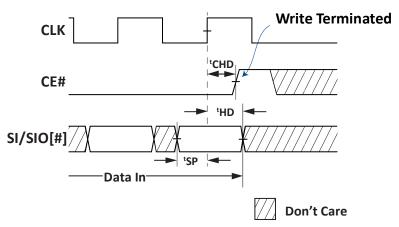
				SPI Mode (C	QE=0)		ľ		QPI Mode (QE=1)
Command	Code	Cmd	Addr	Wait Cycle	DIO	Max Freq.	Cmd	Addr	Wait Cycle	DIO	Max Freq.
Read	'h03	S	S	0	S	33	N/A				
Fast Read	'h0B	S	S	8	S	84	Q	Q	4	Q	66
Fast Read Quad	'hEB	S	Q	6	Q	84	Q	Q	6	Q	84
Write	'h02	S	S	0	S	84	Q	Q	0	Q	84
Quad Write	'h38	S	Q	0	Q	84		same as 'h02			
Enter Quad Mode	'h35	S				84			N/A		
Exit Quad Mode	'hF5			N/A			Q	÷			84
Reset Enable	'h66	S	-	- 3.	-	84	Q		-	В	84
Reset	'h99	S			-	84	Q	-	-		84
Halfsleep [™] Entry	'hC0	S	-		-	84	Q	1	-		84
Read ID	'h9F	S	S	0	S	33	N/A				

Remark: S = Serial IO, Q = Quad IO

8.6 Command Termination

All Reads & Writes must be completed by raising CE# high immediately afterwards in order to terminate the active command and set the device into standby. Not doing so will block internal refresh operations and cause memory failure.

Figure 2 Write Command Termination





For a memory controller to correctly latch the last piece of data prior to read termination, it is recommended to provide a longer CE# hold time (tCHD > tACLK+tCLK) for a sufficient data window

Read Terminated CLK-CE# ^tACLK SO/SIO[#] High-Z Data Out **Don't Care Undefined**

Figure 3 Read Command Termination

9. Halfsleep[™] Mode Operation

Halfsleep[™] mode is a feature which puts the device in an ultra-low power state, while the stored data is retained. HalfsleepTM mode entry can be entered by issuing a command 'hC0 in SPI modes. CE# going high initiates the Halfsleep™ mode and must be maintained for the minimum duration of ^tHS. The HalfsleepTM Entry command sequences are shown below.

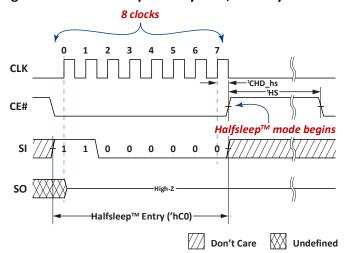
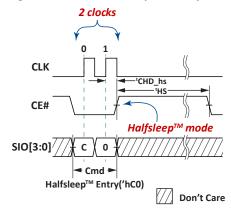


Figure 4 SPI Halfsleep™ Entry 'hC0, SPI only command

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Figure 5 QPI Halfsleep™ Entry 'hC0



Halfsleep™ Exit is initiated by a low pulsed CE#. Afterwards, CE# can be held high with or without clock toggling until the first operation begins (observing minimum tXHS).

Figure 6 Halfsleep[™] Exit **Clocking Optional CLK** CE# SI/SIO[3:0]X Undefined

10. SPI Mode Operations

The device powers up into SPI mode by default but can also be switched into QPI mode.

10.1 Access Using CRE

For all reads, data will be available ^tACLK after the falling edge of CLK.

SPI Reads can be done in three ways:

- 1. 'h03: Serial CMD, Serial Addr/IO, slow frequency.
- 2. 'hOB: Serial CMD, Serial Addr/IO, fast frequency.
- 3. 'hEB: Serial CMD, Quad Addr/IO, fast frequency.



Figure 7 SPI Read 'h03 (max freq 33MHz)

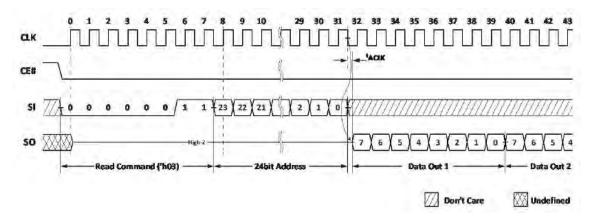


Figure 8 SPI Fast Read 'h0B (max freq 84 MHz)

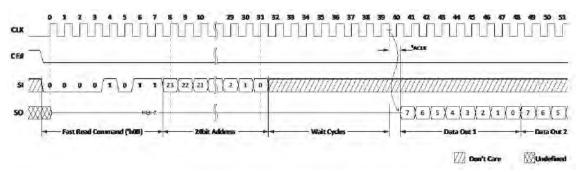
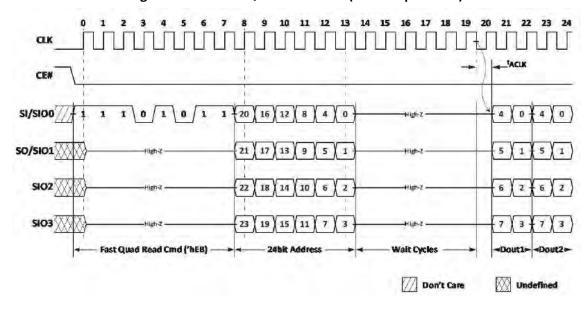


Figure 9 SPI Fast Quad Read 'hEB (max freq 84 MHz)





10.2 SPI Write Operations

Figure 10 SPI Write 'h02

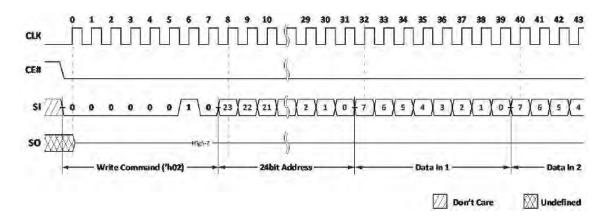
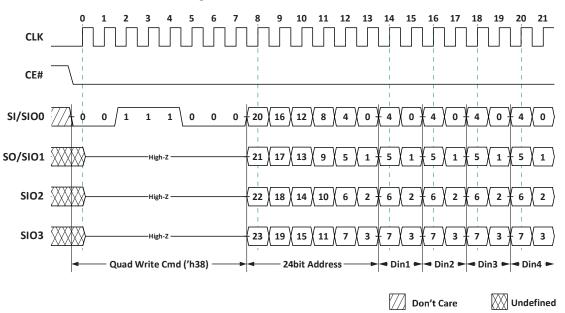


Figure 11 SPI Quad Write 'h38



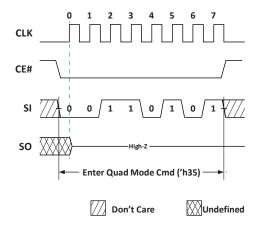
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10.3 SPI Quad Mode Enable Operation

Figure 12 Quad Mode Enable 'h35 (available only in SPI mode)



11. Read ID

Read ID command provides information of vendor ID, device density, and manufacturing ID. Note that Read ID command can be used ONLY as Power up initialization after the device Reset tRST ≥ 50ns right after Global Reset command.

Figure 13 Pre-condition of EID Read

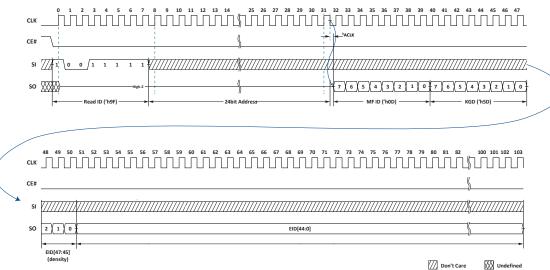




11.1 SPI Read ID Operations

This command is similar to Fast Read, but without the wait cycles and the device outputs EID value instead of data.

Figure 14 SPI Read ID 'h9F (available only in SPI mode)



12. QPI Mode Operations

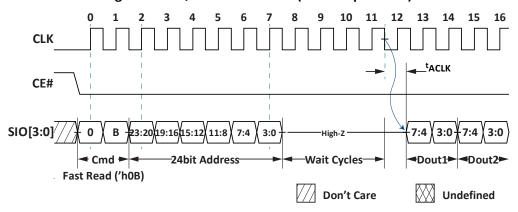
12.1 QPI Mode Operations

For all reads, data will be available ^tACLK after the falling edge of CLK.

QPI Reads can be done in one of two ways:

- 1. 'hOB: Quad CMD, Quad Addr/IO, slow frequency
- 2. 'hEB: Quad CMD, Quad Addr/IO, fast frequency

Figure 15 QPI Fast Read 'h0B (max freq 66 MHz)



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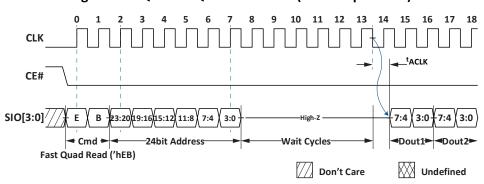
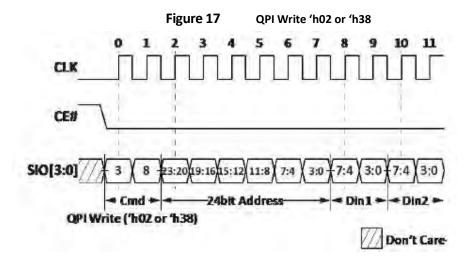


Figure 16 QPI Fast Quad Read 'hEB (max freq 84 MHz)

12.2 QPI Write Operations

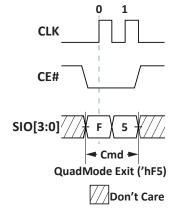
QPI write command can be input as 'h02 or 'h38.



12.3 QPI Quad Mode Exit Operation

This command will switch the device back into serial IO mode.

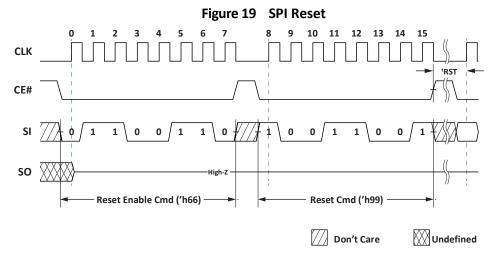
Figure 18 Quad Mode Exit 'hF5 (only available in QPI mode)

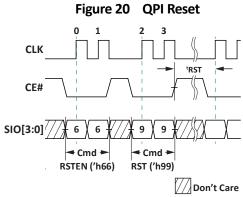




13. Reset Operation

The Reset operation is used as a system (software) reset that puts the device in SPI standby mode which is also the default mode after power-up. This operation consists of two commands: Reset-Enable (RSTEN) and Reset (RST).





Reset command has to immediately follow the Reset-Enable command in order for the reset operation to take effect. Any command other than the Reset command after the Reset-Enable command will cause the device to exit Reset-Enable state and abandon reset operation.



14. Input/Output Timing



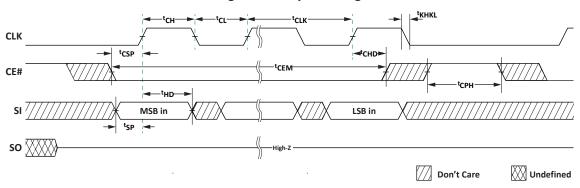
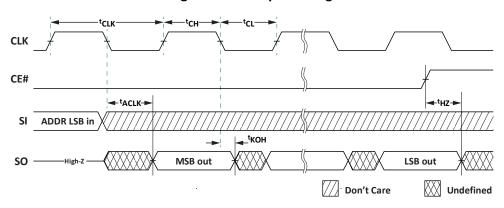


Figure 22 Output Timing



15. Electrical Specifications

15.1 Absolute Maximum Ratings

Table 3 Absolute Maximum Ratings

Parameter	Symbol	Rating	Unit	Notes
Voltage to any ball except V _{DD} relative to	VT	-0.4 to V _{DD} +0.4	V	
Voltage on V _{DD} supply relative to V _{SS}	V_{DD}	-0.4 to +2.45	V	
Storage Temperature	T _{STG}	-55 to +150	°C	1

Notes: Storage temperature refers to the case surface temperature on the center/top side of the PSRAM. Caution:

Exposing the device to stress above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability



15.2 Pin Capacitance

Table 4 Pin Capacitance

Parameter	Symbol	Min	Max	Unit	Notes
Input Pin Capacitance	CIN		6	pF	VIN=0V
Output Pin Capacitance	COUT		8	pF	VOUT=0V

Note: spec'd at 25°C.

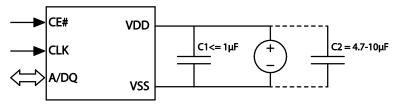
Table 5 Load Capacitance

Parameter	Symbol	Min	Max	Unit	Notes
Load Capacitance	C_L		15	pF	

Note: System C_L for the use of package

15.3 Decoupling Capacitor Requirement

System designers need to take care of power integrity considering voltage regulator response and the memory peak currents/usage modes.



15.3.1 Low ESR cap C1:

It is recommended to place a low ESR decoupling capacitor of $<=1\mu F$ close to the device to absorb transient peaks.

15.3.2 Large cap C2:

During Half-sleep modes even though half-sleep average currents are very small (less than $100\mu A$), device will internally have low duty cycle burst refresh for an extended period of time of a few tens of microseconds. These refresh current peaks are large. During this period if the system regulator cannot supply large peaks for several microseconds, it is important to place a $4.7\mu F-10\mu F$ cap to take care of burst refresh currents and replenish the charge before next burst of refreshes.



15.4 Operating Conditions

Table 6 Operating Characteristics

Parameter	Min	Max	Unit	Notes
Operating Temperature (extended)	-40	105	°C	
Operating Temperature (standard)	-40	85	°C	

15.5 DC Characteristics

Table 7 DC Characteristics

Symbol	Parameter	Min	Max	Unit	Notes
V_{DD}	Supply Voltage	1.62	1.98	V	
V _{IH}	Input high voltage	V _{DD} -0.4	V _{DD} +0.2	V	
V _{IL}	Input low voltage	-0.2	0.4	V	
V _{OH}	Output high voltage (I _{OH} =-0.2mA)	0.8 V _{DD}		V	
V _{OL}	Output low voltage (I _{OL} =+0.2mA)		0.2 V _{DD}	V	
ILI	Input leakage current		1	μΑ	
I _{LO}	Output leakage current		1	μΑ	
I _{CC}	Read/Write		7	mA	1,2
ISB _{EXT}	Standby current (105C)		300	μΑ	3
ISB _{STD}	Standby current (85C)		200	μΑ	3

Note:

- 1. Output load current not included.
- 2. 50% bus toggling rate
- 3. Standby current is measured when CLK is in DC low state.
- 4. Typical ISB_{STDROOM} is 66uA.
- 5. Typical ISB_{STD_HS} is 20uA.



15.6 AC Characteristics

Table 8 Read/Write Timing

Symbol	Parameter	Min	Max	Unit	Notes
	CLK period - SPI Read ('h03)	30.3			33MHz
	CLK period - QPI Read ('h0B)	15.1			66MHz
^t CLK	CLK period - all other operations	7		ns	84MHz*1,2
^t CH/ ^t CL	Clock high/low width		0.55	^t CLK(min)	
tKHKL	CLK rise or fall time		1.5	ns	3
^t CPH	CE# HIGH between subsequent burst operations	18		ns	
^t CEM	CE# low pulse width		3	μs	Extended grade
	CENTOW Paide Width		8		Standard grade
^t CSP	CE# setup time to CLK rising edge PKG	2.5		ns	
^t CHD	CE# hold time from CLK rising edge	3.0		ns	2
^t CHD_HS	CE# hold time from CLK rising edge for Halfsleep™ Entry command	6		ns	
^t SP	Setup time to active CLK edge	2		ns	
^t HD	Hold time from active CLK edge	2		ns	
^t HZ	Chip disable to DQ output high-Z		5.5	ns	
^t ACLK	CLK to output delay	2	5.5	ns	
^t KOH	Data hold time from clock falling edge	1.5		ns	
tHS	Minimum Half Sleep duration	150		us	
tXHS	Halfsleep [™] Exit CE# low to CLK setup	150		us	
^t XPHS	Halfsleep [™] Exit CE# low pulse width	60		ns	
			tCEM	us	Standard temp
				us	Extended temp
^t RST	Time between end of RST CMD to next	50		ns	

Note: 1. Frequency limits are therefore: 84MHz max when burst commands cross page boundary

- 2. System max C_L 15pF for the use of package.
- 3. Measured from 20% to 80% of VDD





17. Revision History

Vision	Who	Date	Description
1	William CHEN	Jan 17 2022	Initial branded release